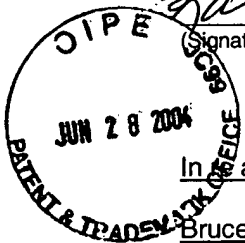


IFW

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to : Commissioner of Patents and Trademarks, Alexandria, VA.22313, on June 25, 2004. The applicant and/or attorney requests the date of deposit as the filing date. Depositor: Karen Cinq-Mars

*Karen Cinq-Mars* 6/25/04  
(Signature & date)



**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re application of \_\_\_\_\_:

Bruce B. Doris et al. :

Group Art Unit: 2812

Serial No.10/605,672 :

Examiner: Stanetta D. Isaac

Filed: 10/16/2003 :

International Business Machines Corporation  
2070 Route 52  
Hopewell Junction, NY 12533

TITLE: High Performance Strained CMOS Devices

**INFORMATION DISCLOSURE STATEMENT**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

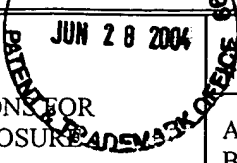
Pursuant to the duty of disclosure set forth in 37 C.F.R. 1.56, and further pursuant to the provisions of 37 C.F.R. 1.97 and 1.98, applicants hereby respectfully submit copies of the non-US patents and publications as listed on Form PTO-1449, attached hereto.

In citing these documents, no representation is made nor intended as to the pertinency or non-pertinency of the art, that better art than that listed is not available, or that other art is not applicable.

The Commissioner is hereby authorized to charge the fees for this submission to Deposit Account No. 09-0458.

Respectfully submitted,  
Bruce B. Doris et al.

By *Joseph P. Abate* 6-24-04  
Joseph P. Abate, Attorney  
Registration No. 30,238  
Telephone No. 845-894-4633

FORM PTO-1449 (Modified)		ATTY. DOCKET NO. IS920030247US1	SERIAL NO. 10/605,672
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT	APPLICANT: Bruce B. Doris, et al.		
(Use several sheets if necessary)	FILING DATE: 10/16/03	GROUP: 2812	

## REFERENCE DESIGNATION

## U.S. PATENT DOCUMENTS

EXAMINER INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPRO.)
	6,228,694 B1	5/8/2001	Doyle et al.			
	6,406,973 B1	6/18/2002	Lee			
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DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
					YES	NO

## OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)

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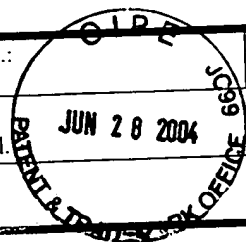
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LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S  
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Page 1 of 1

Attorney Docket No.:  
FIS920030247Applicant:  
Bruce B. Doris, et al.Filing Date:  
10/16/03Serial No.:  
10/605,672Group:  
2812

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